

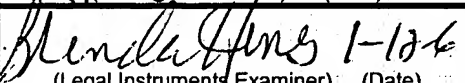


**Issue Classification**

<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
10/771,396	HOJO ET AL.	
<b>Examiner</b>	<b>Art Unit</b>	
Rip A. Lee	1713	

ISSUE CLASSIFICATION													
ORIGINAL					CROSS REFERENCE(S)								
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
525		333.1			525	332.6	333.5						
INTERNATIONAL CLASSIFICATION					524	161	157	157	161	173	201	202	
C	0	8	F	136/08	524	203							
C	0	8	F	12/08									
C	0	8	K	5/42									
C	0	8	K	5/36									
				1									

 (Assistant Examiner)	Jan 12, 2006 (Date)	 <b>DAVID W. WU</b> SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 1700 (Primary Examiner)	1/12/06 (Date)	Total Claims Allowed: 11
 (Legal Instruments Examiner)	1-12-06 (Date)			O.G. Print Claim(s) 1
				O.G. Print Fig. ---

[illegible]